Measurement Report for Device, P1 GSM850_GPRS 4TS_Right Cheek_Ch 251

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	GSM 850	GSM,	848.800,	9.7	0.927	43.1
HSL	0.00		10090-DAC	251			

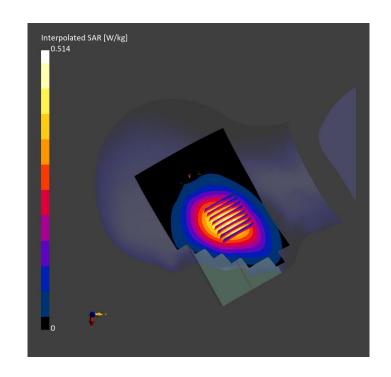
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date	
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Feb-28	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08	
2097				

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-02-28	2025-02-28
psSAR1g [W/kg]	0.411	0.441
psSAR10g [W/kg]	0.282	0.350
Power Drift [dB]	-0.05	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		96.9
Dist 3dB Peak [mm]		26.5



Measurement Report for Device, P2 GSM1900_GPRS 4TS_Right Cheek_Ch 512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	PCS 1900	GSM,	1850.200,	7.77	1.38	39.8
HSL	0.00		10090-DAC	512			

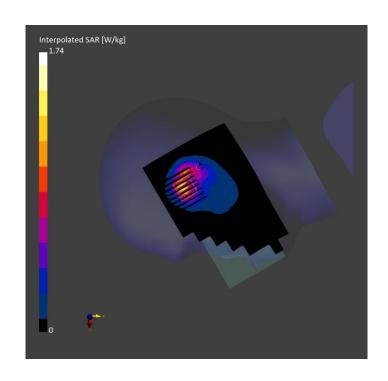
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date	
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08	
2097				

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-02	2025-03-02
psSAR1g [W/kg]	0.952	0.963
psSAR10g [W/kg]	0.525	0.512
Power Drift [dB]	-0.09	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.1
Dist 3dB Peak [mm]		10.7



Measurement Report for Device, P3 WCDMA II_RMC12.2K_Right Cheek_Ch 9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 2	WCDMA,	1852.400,	7.77	1.38	39.8
ISH	0.00		10011-CAC	9262			

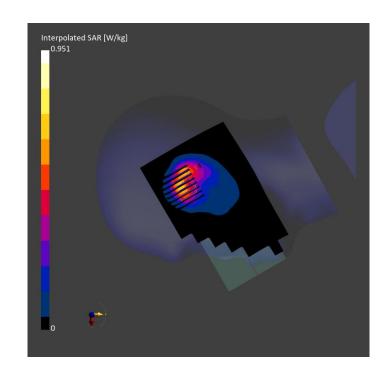
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-02	2025-03-02
psSAR1g [W/kg]	0.548	0.545
psSAR10g [W/kg]	0.308	0.301
Power Drift [dB]	-0.02	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.1
Dist 3dB Peak [mm]		10.8



Measurement Report for Device, P4 WCDMA IV_RMC12.2K_Right Cheek_Ch 1513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 4	WCDMA,	1752.600,	8.01	1.33	40.1
ISH	0.00		10011-CAC	1513			

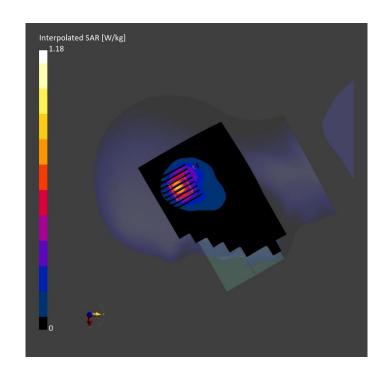
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-03	2025-03-03
psSAR1g [W/kg]	0.652	0.664
psSAR10g [W/kg]	0.344	0.345
Power Drift [dB]	-0.08	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.6
Dist 3dB Peak [mm]		9.9



Measurement Report for Device, P5 WCDMA V_RMC12.2K_Right Cheek_Ch 4132

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 5	WCDMA,	826.400,	9.7	0.919	43.2
ISH	0.00		10011-CAC	4132			

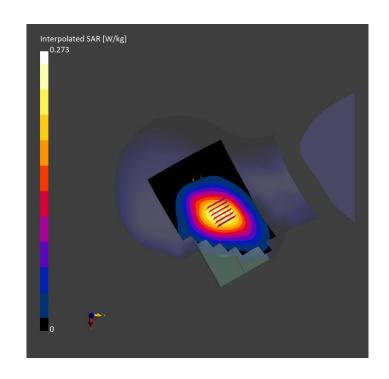
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Feb-28	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-02-28	2025-02-28
psSAR1g [W/kg]	0.219	0.236
psSAR10g [W/kg]	0.152	0.187
Power Drift [dB]	-0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		97.5
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P6 LTE 2_QPSK20M_Right Cheek_Ch 18700_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 2	LTE-FDD,	1860.000,	7.77	1.39	39.8
HSL	0.00		10169-CAF	18700			

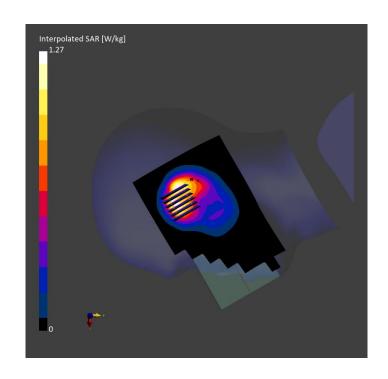
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-02	2025-03-02
psSAR1g [W/kg]	0.645	0.725
psSAR10g [W/kg]	0.373	0.397
Power Drift [dB]	0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.0
Dist 3dB Peak [mm]		9.6



Measurement Report for Device, P7 LTE 66&4_QPSK20M_Right Cheek_Ch 132572_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 66	LTE-FDD,	1770.000,	8.01	1.34	40.0
ISH	0.00		10169-CAF	132572			

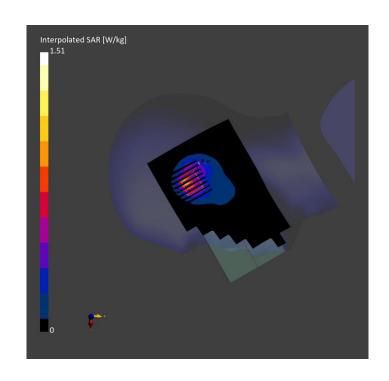
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-03	2025-03-03
psSAR1g [W/kg]	0.739	0.844
psSAR10g [W/kg]	0.405	0.440
Power Drift [dB]	-0.02	0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.3
Dist 3dB Peak [mm]		9.6



Measurement Report for Device, P8 LTE 5_QPSK10M_Right Cheek_Ch 20600_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 5	LTE-FDD,	844.000,	9.7	0.925	43.1
HSL	0.00		10175-CAH	20600			

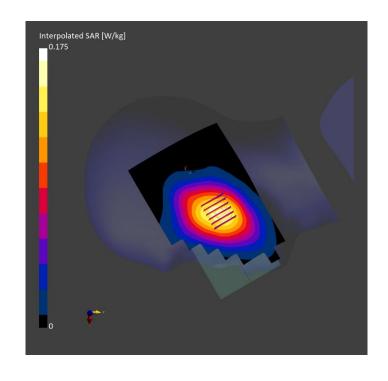
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Feb-28	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-02-28	2025-02-28
psSAR1g [W/kg]	0.139	0.150
psSAR10g [W/kg]	0.096	0.119
Power Drift [dB]	-0.00	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		96.4
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P9 LTE 12&17_QPSK10M_Right Cheek_Ch 23095_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 12	LTE-FDD,	707.500,	9.99	0.877	43.5
ISH	0.00		10175-CAH	23095			

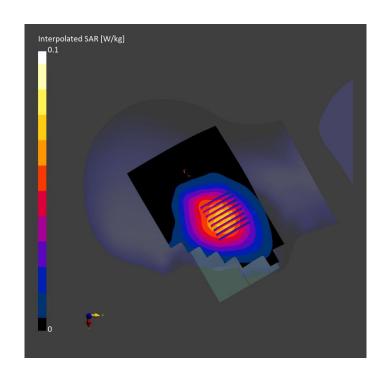
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-01	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-01	2025-03-01
psSAR1g [W/kg]	0.064	0.067
psSAR10g [W/kg]	0.044	0.054
Power Drift [dB]	-0.09	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		98.6
Dist 3dB Peak [mm]		25.2



Measurement Report for Device, P10 LTE 41_QPSK20M_Right Cheek_Ch 41490_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 41	LTE-TDD,	2680.000,	7.29	1.95	39.7
HSL	0.00		10172-CAH	41490			

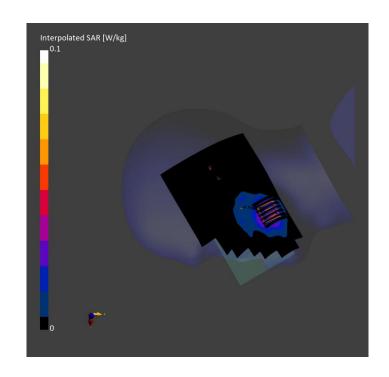
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.041	0.039
psSAR10g [W/kg]	0.020	0.020
Power Drift [dB]	-0.06	0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.0
Dist 3dB Peak [mm]		10.6



Measurement Report for Device, P11 LTE 71_QPSK20M_Right Cheek_Ch 133322_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 71	LTE-FDD,	683.000,	9.99	0.869	43.5
HSL	0.00		10169-CAF	133322			

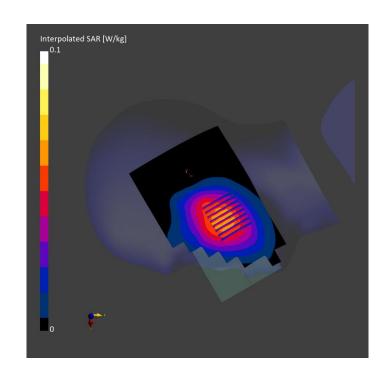
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-01	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-01	2025-03-01
psSAR1g [W/kg]	0.059	0.062
psSAR10g [W/kg]	0.041	0.050
Power Drift [dB]	-0.03	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		98.5
Dist 3dB Peak [mm]		27.2



Measurement Report for Device, P12 N71_DFT-s-OFDM BPSK 20M_Right Cheek_Ch 134600_1RB_OS53

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band n71	5G NR FR1 FDD,	673.000,	9.99	0.865	43.6
HSL	0.00		10931-AAC	134600			

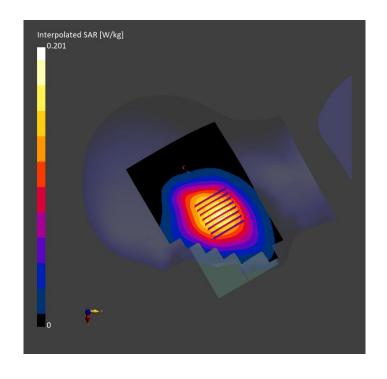
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-01	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-01	2025-03-01
psSAR1g [W/kg]	0.155	0.173
psSAR10g [W/kg]	0.109	0.141
Power Drift [dB]	0.10	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		95.2
Dist 3dB Peak [mm]		28.8



Measurement Report for Device, P13 802.11b_Left Cheek_Ch 11

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	WLAN	WLAN,	2462.000,	7.25	1.80	39.9
ISH	0.00	2 4GHz	10315-AAR	11			

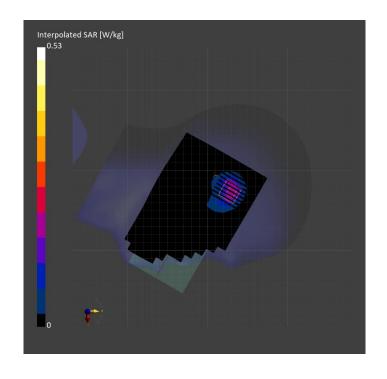
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.171	0.170
psSAR10g [W/kg]	0.086	0.085
Power Drift [dB]	0.11	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.3
Dist 3dB Peak [mm]		8.5



Measurement Report for Device, P14 802.11a_Left Cheek_Ch 36

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	U-NII-1, U-	WLAN,	5180.000,	5.45	4.55	37.3
ISH	0.00	NII-2A	10317-AAF	36			

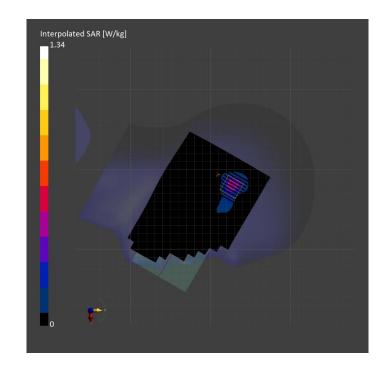
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-05	2025-03-05
psSAR1g [W/kg]	0.385	0.404
psSAR10g [W/kg]	0.140	0.136
Power Drift [dB]	-0.01	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		65.5
Dist 3dB Peak [mm]		8.1



Measurement Report for Device, P15 802.11n_HT20_Left Cheek_Ch 149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	U-NII-2C, U-	WLAN,	5745.000,	4.98	5.18	36.2
HSL	0.00	NII-3	10591-AAD	149			

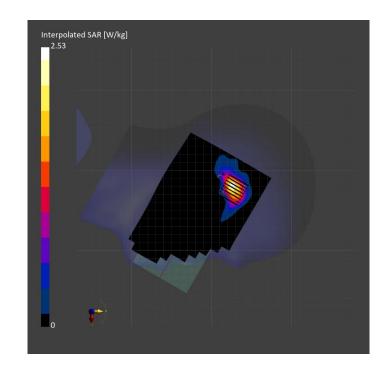
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-05	2025-03-05
psSAR1g [W/kg]	0.561	0.612
psSAR10g [W/kg]	0.202	0.203
Power Drift [dB]	-0.04	0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		59.8
Dist 3dB Peak [mm]		7.4



Measurement Report for Device, P16 BT_1 DH5_Left Cheek_Ch 39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	ISM 2.4 GHz	Bluetooth,	2441.000,	7.25	1.78	39.9
ISH	0.00	Band	10032-CAA	39			

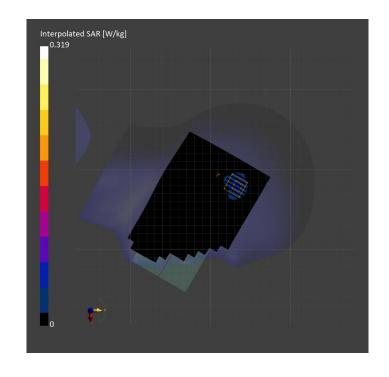
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.044	0.040
psSAR10g [W/kg]	0.022	0.020
Power Drift [dB]	-0.04	0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.9
Dist 3dB Peak [mm]		10.3



Measurement Report for Device, P17 GSM850_GPRS 4TS_Rear Face_1cm_Ch 251

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	GSM 850	GSM,	848.800,	9.7	0.927	43.1
HSL	10.00		10090-DAC	251			

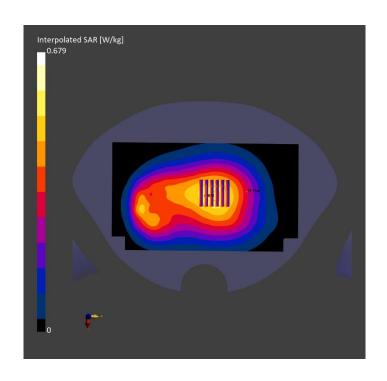
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Feb-28	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-02-28	2025-02-28
psSAR1g [W/kg]	0.494	0.521
psSAR10g [W/kg]	0.346	0.403
Power Drift [dB]	0.05	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.4
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P18 GSM1900_GPRS 4TS_Rear Face_1cm_Ch 661

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	PCS 1900	GSM,	1880.000,	7.77	1.39	39.8
ISH	10.00		10090-DAC	661			

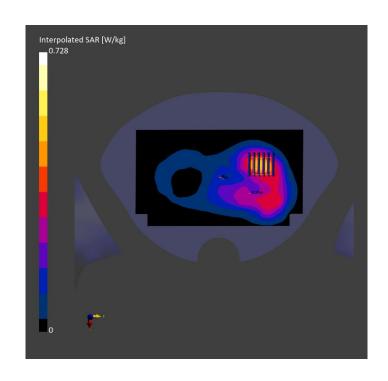
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-02	2025-03-02
psSAR1g [W/kg]	0.459	0.466
psSAR10g [W/kg]	0.265	0.284
Power Drift [dB]	-0.02	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.4
Dist 3dB Peak [mm]		14.4



Measurement Report for Device, P19 WCDMA II_RMC12.2K_Rear Face_1cm_Ch 9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 2	WCDMA,	1852.400,	7.77	1.38	39.8
ISH	10.00		10011-CAC	9262			

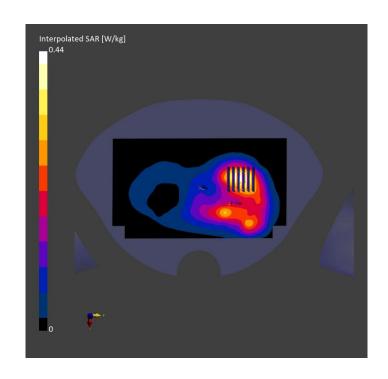
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-02	2025-03-02
psSAR1g [W/kg]	0.267	0.288
psSAR10g [W/kg]	0.152	0.175
Power Drift [dB]	-0.12	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.3
Dist 3dB Peak [mm]		14.4



Measurement Report for Device, P20 WCDMA IV_RMC12.2K_Rear Face_1cm_Ch 1513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 4	WCDMA,	1752.600,	8.01	1.33	40.1
HSI	10.00		10011-CAC	1513			

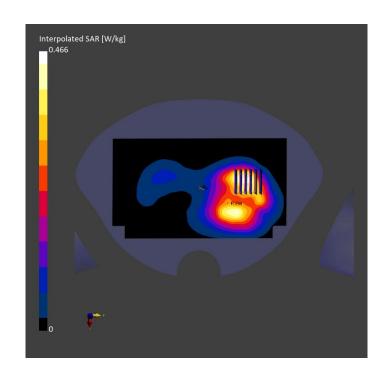
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-03	2025-03-03
psSAR1g [W/kg]	0.281	0.298
psSAR10g [W/kg]	0.165	0.181
Power Drift [dB]	-0.01	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.1
Dist 3dB Peak [mm]		11.9



Measurement Report for Device, P21 WCDMA V_RMC12.2K_Rear Face_1cm_Ch 4132

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 5	WCDMA,	826.400,	9.7	0.919	43.2
HSL	10.00		10011-CAC	4132			

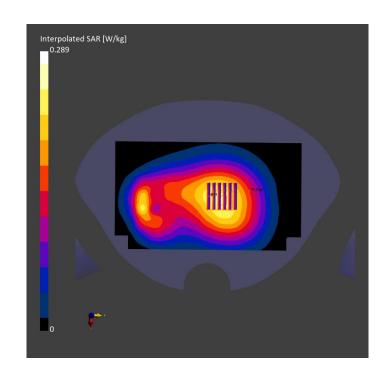
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Feb-28	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-02-28	2025-02-28
psSAR1g [W/kg]	0.219	0.228
psSAR10g [W/kg]	0.154	0.177
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		93.3
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P22 LTE 2_QPSK20M_Rear Face_1cm_Ch 18700_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 2	LTE-FDD,	1860.000,	7.77	1.39	39.8
HSL	10.00		10169-CAF	18700			

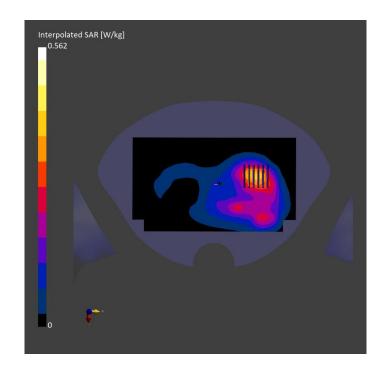
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-02	2025-03-02
psSAR1g [W/kg]	0.346	0.367
psSAR10g [W/kg]	0.203	0.226
Power Drift [dB]	-0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.3
Dist 3dB Peak [mm]		14.6



Measurement Report for Device, P23 LTE 66&4_QPSK20M_Rear Face_1cm_Ch 132572_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 66	LTE-FDD,	1770.000,	8.01	1.34	40.0
ISH	10.00		10169-CAF	132572			

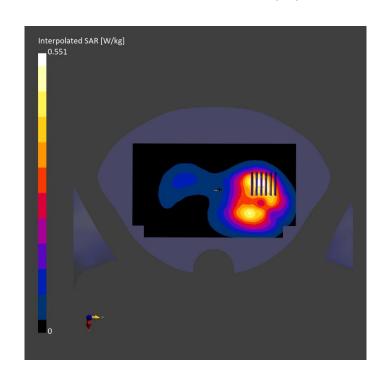
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-03	2025-03-03
psSAR1g [W/kg]	0.326	0.366
psSAR10g [W/kg]	0.193	0.225
Power Drift [dB]	-0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.4
Dist 3dB Peak [mm]		12.8



Measurement Report for Device, P24 LTE 5_QPSK10M_Rear Face_1cm_Ch 20600_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 5	LTE-FDD,	844.000,	9.7	0.925	43.1
HSL	10.00		10175-CAH	20600			

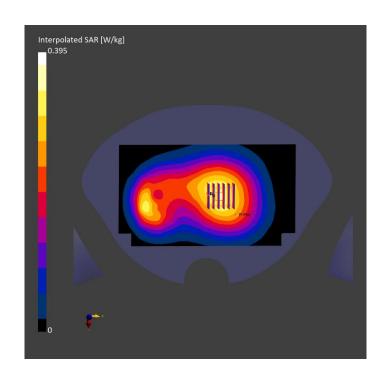
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Feb-28	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-02-28	2025-02-28
psSAR1g [W/kg]	0.295	0.312
psSAR10g [W/kg]	0.207	0.241
Power Drift [dB]	0.05	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		93.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P25 LTE 12&17_QPSK10M_Rear Face_1cm_Ch 23095_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 12	LTE-FDD,	707.500,	9.99	0.877	43.5
HSL	10.00		10175-CAH	23095			

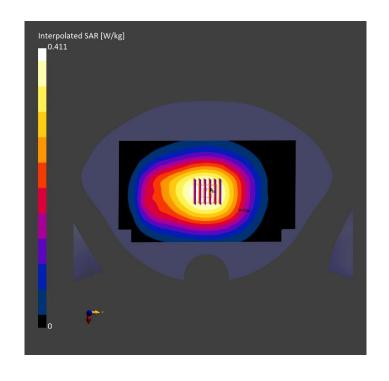
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date	
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-01	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08	
2097				

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-01	2025-03-01
psSAR1g [W/kg]	0.306	0.323
psSAR10g [W/kg]	0.219	0.252
Power Drift [dB]	0.04	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		92.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P26 LTE 41_QPSK20M_Rear Face_1cm_Ch 41490_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 41	LTE-TDD,	2680.000,	7.29	1.95	39.7
HSL	10.00		10172-CAH	41490			

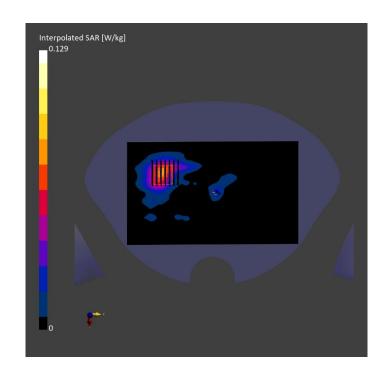
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date	
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08	
2097				

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.063	0.072
psSAR10g [W/kg]	0.032	0.036
Power Drift [dB]	0.08	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.3
Dist 3dB Peak [mm]		11.4



Measurement Report for Device, P27 LTE 71_QPSK20M_Rear Face_1cm_Ch 133322_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 71	LTE-FDD,	683.000,	9.99	0.869	43.5
ISH	10.00		10169-CAF	133322			

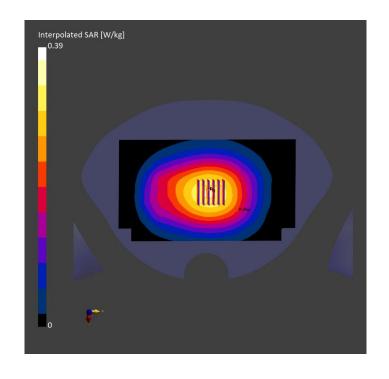
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-01	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-01	2025-03-01
psSAR1g [W/kg]	0.292	0.306
psSAR10g [W/kg]	0.209	0.240
Power Drift [dB]	0.04	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		92.5
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P28 N71_DFT-s-OFDM BPSK 20M_Rear Face_1cm_Ch 134600_1RB_OS53)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n71	5G NR FR1 FDD,	673.000,	9.99	0.865	43.6
HSL	10.00		10931-AAC	134600			

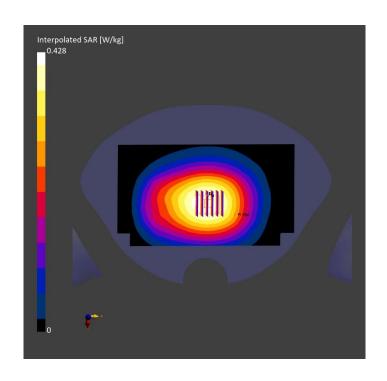
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-01	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-01	2025-03-01
psSAR1g [W/kg]	0.319	0.334
psSAR10g [W/kg]	0.229	0.260
Power Drift [dB]	-0.04	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P29 802.11b_Rear Face_1cm_Ch 11

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	WLAN	WLAN,	2462.000,	7.25	1.88	37.7
ISH	10.00	2 4GHz	10315-AAB	11			

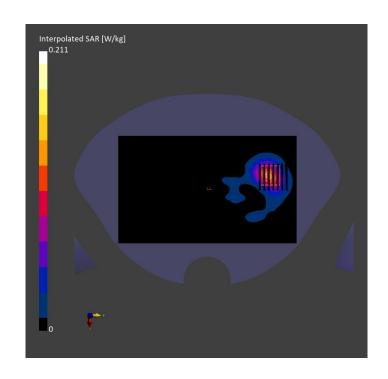
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.104	0.107
psSAR10g [W/kg]	0.052	0.051
Power Drift [dB]	-0.09	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.8
Dist 3dB Peak [mm]		9.9



Measurement Report for Device, P30 802.11a_Rear Face_1cm_Ch 36

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	U-NII-1, U-	WLAN,	5180.000,	5.45	4.55	37.3
ISH	10.00	NII-2A	10317-AAF	36			

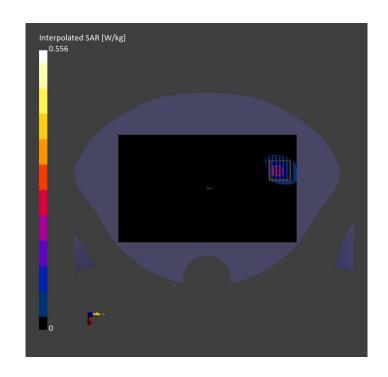
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.144	0.152
psSAR10g [W/kg]	0.051	0.048
Power Drift [dB]	0.03	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.8
Dist 3dB Peak [mm]		8.0



Measurement Report for Device, P31 802.11n_HT20_Front Face_1cm_Ch 149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	FRONT,	U-NII-2C, U-	WLAN,	5745.000,	4.98	5.18	36.2
HSL	10.00	NII-3	10591-AAD	149			

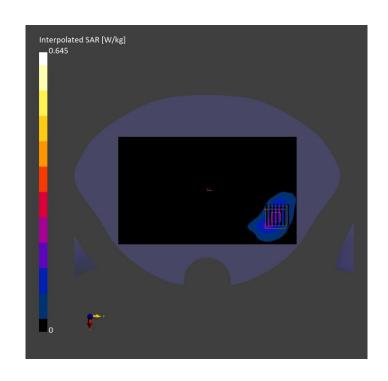
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-05	2025-03-05
psSAR1g [W/kg]	0.141	0.152
psSAR10g [W/kg]	0.058	0.054
Power Drift [dB]	-0.01	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		58.4
Dist 3dB Peak [mm]		8.7



Measurement Report for Device, P32 BT_1DH5_Rear Face_1cm_Ch 39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	ISM 2.4 GHz	Bluetooth,	2441.000,	7.25	1.85	39.5
ISH	10.00	Band	10032-CAA	39			

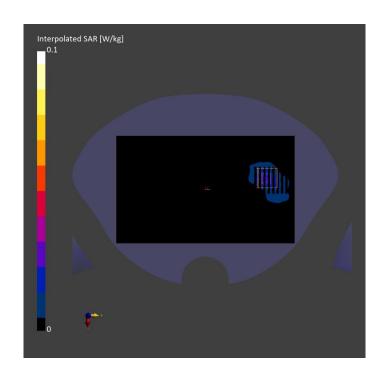
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.021	0.023
psSAR10g [W/kg]	0.010	0.01
Power Drift [dB]	-0.06	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.2
Dist 3dB Peak [mm]		7.0



Measurement Report for Device, P33 GSM850_GPRS 4TS_Rear Face_1cm_Ch 251

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	GSM 850	GSM,	848.800,	9.7	0.927	43.1
HSL	10.00		10090-DAC	251			

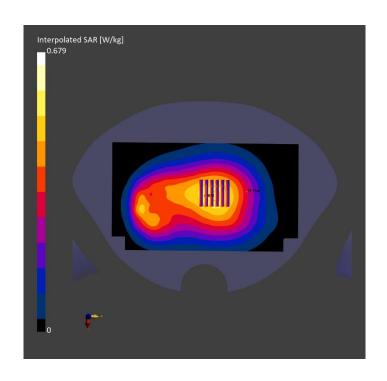
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Feb-28	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-02-28	2025-02-28
psSAR1g [W/kg]	0.494	0.521
psSAR10g [W/kg]	0.346	0.403
Power Drift [dB]	0.05	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.4
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P34 GSM1900_GPRS 4TS_Rear Face_1cm_Ch 661

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	PCS 1900	GSM,	1880.000,	7.77	1.39	39.8
HSL	10.00		10090-DAC	661			

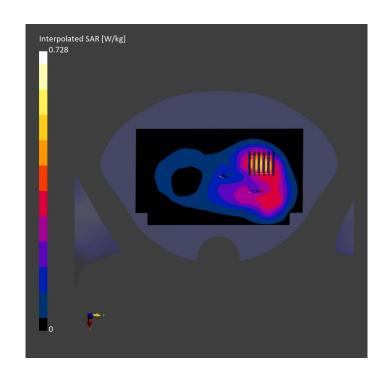
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-02	2025-03-02
psSAR1g [W/kg]	0.459	0.466
psSAR10g [W/kg]	0.265	0.284
Power Drift [dB]	-0.02	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.4
Dist 3dB Peak [mm]		14.4



Measurement Report for Device, P35 WCDMA II_RMC12.2K_Rear Face_1cm_Ch 9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 2	WCDMA,	1852.400,	7.77	1.38	39.8
ISH	10.00		10011-CAC	9262			

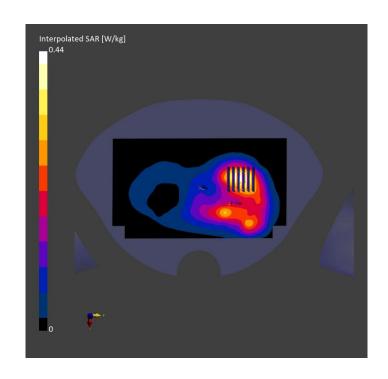
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-02	2025-03-02
psSAR1g [W/kg]	0.267	0.288
psSAR10g [W/kg]	0.152	0.175
Power Drift [dB]	-0.12	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.3
Dist 3dB Peak [mm]		14.4



Measurement Report for Device, P36 WCDMA IV_RMC12.2K_Rear Face_1cm_Ch 1513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 4	WCDMA,	1752.600,	8.01	1.33	40.1
HSL	10.00		10011-CAC	1513			

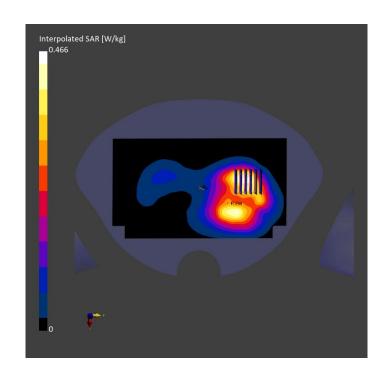
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-03	2025-03-03
psSAR1g [W/kg]	0.281	0.298
psSAR10g [W/kg]	0.165	0.181
Power Drift [dB]	-0.01	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.1
Dist 3dB Peak [mm]		11.9



Measurement Report for Device, P37 WCDMA V_RMC12.2K_Rear Face_1cm_Ch 4132

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 5	WCDMA,	826.400,	9.7	0.919	43.2
HSL	10.00		10011-CAC	4132			

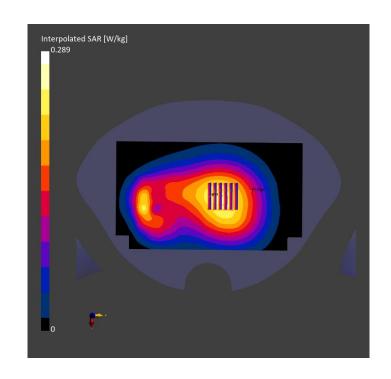
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Feb-28	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-02-28	2025-02-28
psSAR1g [W/kg]	0.219	0.228
psSAR10g [W/kg]	0.154	0.177
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		93.3
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P38 LTE 2_QPSK20M_Rear Face_1cm_Ch 18700_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 2	LTE-FDD,	1860.000,	7.77	1.39	39.8
HSL	10.00		10169-CAF	18700			

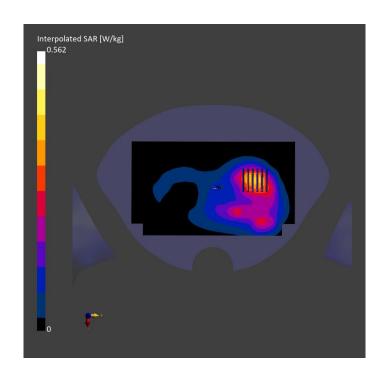
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-02	2025-03-02
psSAR1g [W/kg]	0.346	0.367
psSAR10g [W/kg]	0.203	0.226
Power Drift [dB]	-0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.3
Dist 3dB Peak [mm]		14.6



Measurement Report for Device, P39 LTE 66&4_QPSK20M_Rear Face_1cm_Ch 132572_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 66	LTE-FDD,	1770.000,	8.01	1.34	40.0
ISH	10.00		10169-CAF	132572			

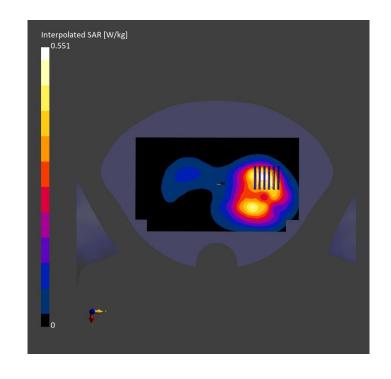
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-03	2025-03-03
psSAR1g [W/kg]	0.326	0.366
psSAR10g [W/kg]	0.193	0.225
Power Drift [dB]	-0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.4
Dist 3dB Peak [mm]		12.8



Measurement Report for Device, P40 LTE 5_QPSK10M_Rear Face_1cm_Ch 20600_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 5	LTE-FDD,	844.000,	9.7	0.925	43.1
HSL	10.00		10175-CAH	20600			

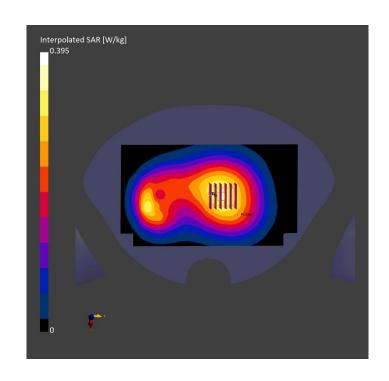
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Feb-28	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-02-28	2025-02-28
psSAR1g [W/kg]	0.295	0.312
psSAR10g [W/kg]	0.207	0.241
Power Drift [dB]	0.05	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		93.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P41 LTE 12&17_QPSK10M_Rear Face_1cm_Ch 23095_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 12	LTE-FDD,	707.500,	9.99	0.877	43.5
HSL	10.00		10175-CAH	23095			

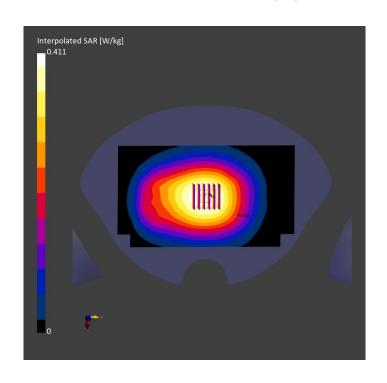
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-01	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

Area Scan	Zoom Scan
120.0 x 210.0	30.0 x 30.0 x 30.0
15.0 x 15.0	6.0 x 6.0 x 1.5
3.0	1.4
N/A	Yes
N/A	1.5
N/A	N/A
VMS + 6p	VMS + 6p
Measured	Measured
	120.0 x 210.0 15.0 x 15.0 3.0 N/A N/A N/A VMS + 6p

	Area Scan	Zoom Scan
Date	2025-03-01	2025-03-01
psSAR1g [W/kg]	0.306	0.323
psSAR10g [W/kg]	0.219	0.252
Power Drift [dB]	0.04	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		92.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P42 LTE 41_QPSK20M_Rear Face_1cm_Ch 41490_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 41	LTE-TDD,	2680.000,	7.29	1.95	39.7
HSL	10.00		10172-CAH	41490			

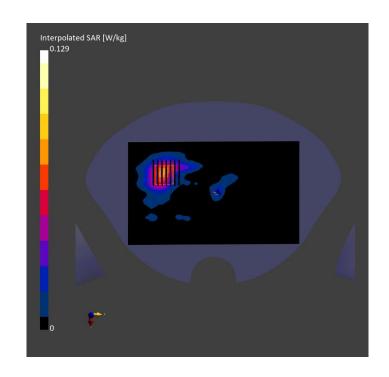
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.063	0.072
psSAR10g [W/kg]	0.032	0.036
Power Drift [dB]	0.08	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.3
Dist 3dB Peak [mm]		11.4



Measurement Report for Device, P43 LTE 71_QPSK20M_Rear Face_1cm_Ch 133322_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 71	LTE-FDD,	683.000,	9.99	0.869	43.5
ISH	10.00		10169-CAF	133322			

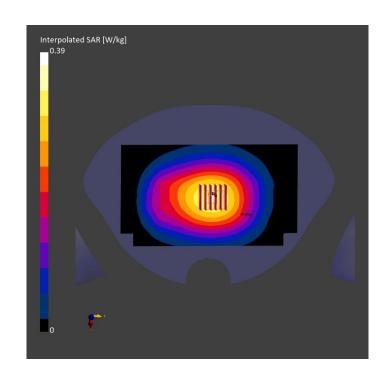
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-01	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

Area Scan	Zoom Scan
120.0 x 210.0	30.0 x 30.0 x 30.0
15.0 x 15.0	6.0 x 6.0 x 1.5
3.0	1.4
N/A	Yes
N/A	1.5
N/A	N/A
VMS + 6p	VMS + 6p
Measured	Measured
	120.0 x 210.0 15.0 x 15.0 3.0 N/A N/A N/A VMS + 6p

	Area Scan	Zoom Scan
Date	2025-03-01	2025-03-01
psSAR1g [W/kg]	0.292	0.306
psSAR10g [W/kg]	0.209	0.240
Power Drift [dB]	0.04	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		92.5
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P44 N71_DFT-s-OFDM BPSK 20M_Rear Face_1cm_Ch 134600_1RB_OS53)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 81.0 x 16.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n71	5G NR FR1 FDD,	673.000,	9.99	0.865	43.6
HSL	10.00		10931-AAC	134600			

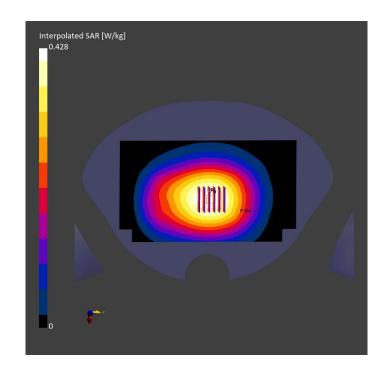
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-01	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-01	2025-03-01
psSAR1g [W/kg]	0.319	0.334
psSAR10g [W/kg]	0.229	0.260
Power Drift [dB]	-0.04	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P45 802.11b_Rear Face_1cm_Ch 11

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	WLAN	WLAN,	2462.000,	7.25	1.88	37.7
HSL	10.00	2.4GHz	10315-AAB	11			

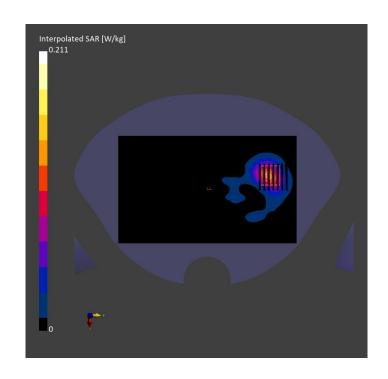
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.104	0.107
psSAR10g [W/kg]	0.052	0.051
Power Drift [dB]	-0.09	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.8
Dist 3dB Peak [mm]		9.9



Measurement Report for Device, P46 802.11a_Rear Face_1cm_Ch 36

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	U-NII-1, U-	WLAN,	5180.000,	5.45	4.55	37.3
ISH	10.00	NII-2A	10317-AAF	36			

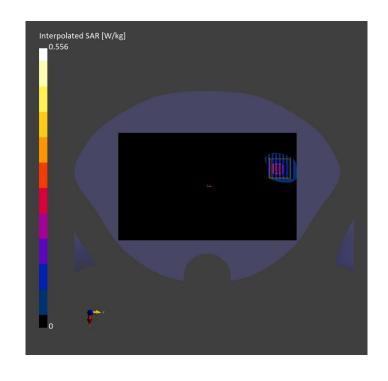
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-05	2025-03-05
psSAR1g [W/kg]	0.144	0.152
psSAR10g [W/kg]	0.051	0.048
Power Drift [dB]	0.03	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.8
Dist 3dB Peak [mm]		8.0



Measurement Report for Device, P47 802.11n_HT20_Front Face_1cm_Ch 149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	FRONT,	U-NII-2C, U-	WLAN,	5745.000,	4.98	5.18	36.2
HSL	10.00	NII-3	10591-AAD	149			

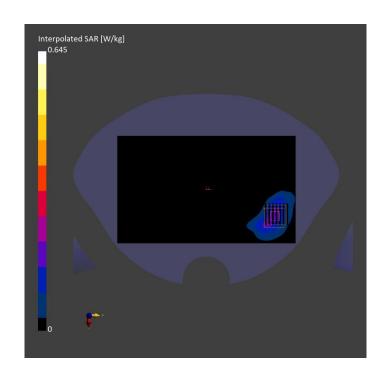
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-05	2025-03-05
psSAR1g [W/kg]	0.141	0.152
psSAR10g [W/kg]	0.058	0.054
Power Drift [dB]	-0.01	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		58.4
Dist 3dB Peak [mm]		8.7



Measurement Report for Device, P48 BT_1DH5_Rear Face_1cm_Ch 39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Smart Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	ISM 2.4 GHz	Bluetooth,	2441.000,	7.25	1.85	39.5
ISH	10.00	Band	10032-CAA	39			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HSL600-10000, 2025-Mar-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08
2097			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.021	0.023
psSAR10g [W/kg]	0.010	0.01
Power Drift [dB]	-0.06	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.2
Dist 3dB Peak [mm]		7.0

